



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : G Laurie Miller et al.                      Art Unit : 2829  
Serial No. : 10/633,276                                      Examiner : Unknown  
Filed : July 31, 2003  
Title : EDDY CURRENT SYSTEM FOR IN-SITU PROFILE MEASUREMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

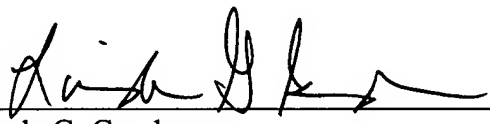
INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 01/07/04

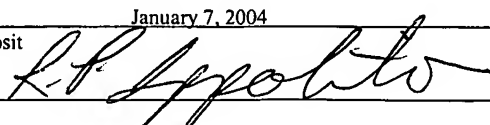
  
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Substitute Form PTO-1449  
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Patent and Trademark OfficeAttorney's Docket No.  
05542-528001Application No.  
10/633,276**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

Applicant  
G Laurie Miller et al.Filing Date  
July 31, 2003

Group Art Unit

(37 CFR §1.98(b))

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0077031 A1	06/20/2002	Johansson et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

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	AQ	
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.